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$\longrightarrow V$	A2			Japan					Abstract	
	А3	4-25176	01/1992 .	Japan					Abstract	
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)										
9/		Tsu-Jae King et al., IEEE ELECTRON DEVICE LETTERS vol 12, no. 10, "A Variable-Work-Function								
	Polycrystalline-Si <sub>1-x</sub> Ge <sub>x</sub> Gate Material for Submicrometer CMOS Technologies, pp. 53								)/91)	
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EXAMINER				DATE CONSIDERED 9/21/2001						
* EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw										
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